

W08104

17w

ATTORNEY DOCKET
068062.0167

PATENT APPLICATION
10/661,873

1



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Edgar Voelkl
Serial No.: 10/661,873
Date Filed: September 12, 2003
Group Art Unit: 2625
Examiner: Couso, Yon Jung
Title: **SYSTEM AND METHOD FOR DETECTING
DIFFERENCES BETWEEN COMPLEX IMAGES**

MAIL STOP - AMENDMENTS
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

I hereby certify that this Information Disclosure Statement is being deposited with the United States Postal Service as Express Mail No. EV351289752US addressed to: Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on November 5, 2004.

Angela Loding

Dear Sir:

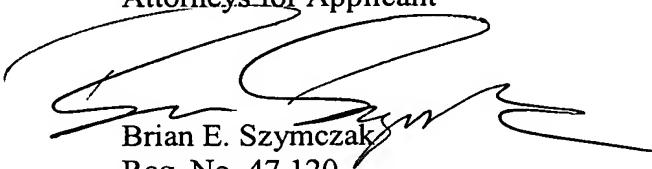
INFORMATION DISCLOSURE STATEMENT

Applicant respectfully requests, pursuant to 37 C.F.R. §§1.56, 1.97 and 1.98, that the references listed on the attached PTO-1449 form be considered and cited in the examination of the above-identified application. A copy of the references is enclosed for the Examiner's convenience. The items contained in this Information Disclosure Statement were first cited in any communication from a foreign patent office in a counterpart foreign application not more than thirty days prior to the filing of this Information Disclosure Statement. Furthermore, pursuant to 37 C.F.R. §§1.97(g) and (h), no representation is made that these references are material to the patentability of the present application.

Applicant believes no fees are due, however, the Commissioner is hereby authorized to charge any fees to Deposit Account No. 50-2148 of Baker Botts L.L.P. in order to effectuate this filing.

Respectfully submitted,

BAKER BOTT S L.L.P.
Attorneys for Applicant



Brian E. Szymczak
Reg. No. 47,120

Date: 11/3/04

Correspondence Address:

Customer No. **31625**

512.322.2548
512.322.8340 (Fax)

PTO-1449		Patent No.	Applicant(s)	
Information Disclosure Citation in an Application		10/661,873	Edgar Voelkl	
NOV 05 2004 U.S. PATENT & TRADEMARK OFFICE		Docket Number	Group Art Unit	Filing Date
		068062.0167	2625	September 12, 2003

U.S. PATENT DOCUMENTS

		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	A.						
	B.						
	C.						
	D.						
	E.						
	F.						
	G.						
	H.						
	I.						
	J.						
	K.						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	L.	196 46 702 A1	5/28/97	DE	G06K	9/62		X
	M.							
	N.							

NON-PATENT DOCUMENTS

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
O.	PCT Invitation to Pay Additional Fees for International Application No. PCT/US03/28877, 6 pages	Mailing Date 10/13/04
P.	C.E. Thomas Jr. et al., "Direct to digital holography for semiconductor wafer defect detection and review" Design, Process Integration, and Characterization for Microelectronics, vol. 4692, XP-002282790, pages 180-194	03/2002
Q.	E. Volkl et al., "Practical Electron Holography: Applications of Advanced Hologram Processing Techniques to Materials Science Problems" Electron Holography, XP008031237, pages 103-116	08/31/94
R.		
S.		

EXAMINER DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.